# **TOSHIBA**

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74AC164P,TC74AC164F,TC74AC164FN,TC74AC164FT

#### 8-Bit Shift Register (S-IN, P-OUT)

The TC74AC164 is an advanced high speed CMOS 8-BIT SERIAL-IN PARALLEL-OUT SHIFT REGISTER fabricated with silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

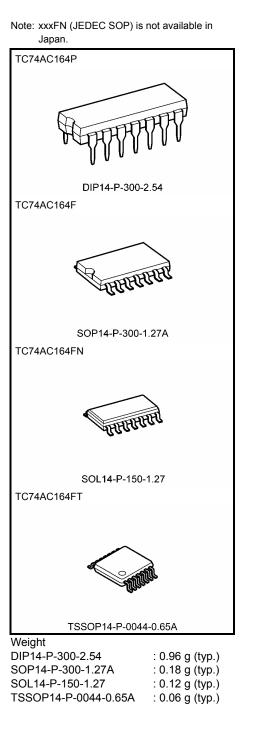
It consists of a serial-in, parallel-out 8-bit shift register with a CLOCK input and an overriding  $\overline{\text{CLEAR}}$  input.

Two serial data inputs (A, B) are provided so that one may be used as a data enable.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

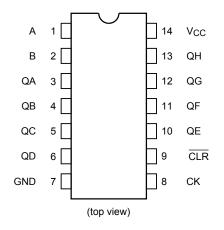
#### Features

- High speed:  $f_{max} = 170 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC}$  = 8  $\mu A$  (max) at Ta = 25°C
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- Symmetrical output impedance: |IOH| = IOL = 24 mA (min) Capability of driving 50 Ω transmission lines.
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: VCC (opr) = 2 V to 5.5 V
- Pin and function compatible with 74F164

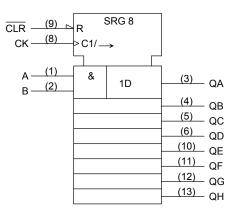


# TOSHIBA

### **Pin Assignment**



## **IEC Logic Symbol**



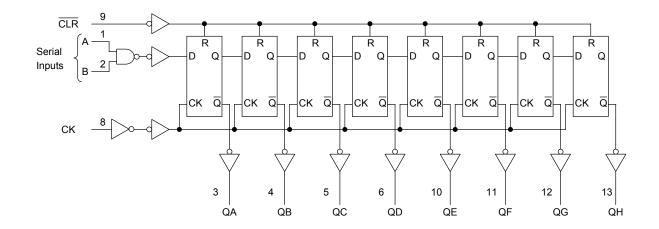
#### Truth Table

	Inp	uts		Outputs					
CLR	СК	Serial In		~	QB				
		А	В	QA	QD		QH		
L	Х	Х	Х	L	L		L		
Н		Х	Х	No Change					
Н		L	Х	L	QA <sub>n</sub>		QGn		
Н		Х	L	L	QAn		QGn		
Н		Н	Н	Н	QAn		QGn		

X: Don't care

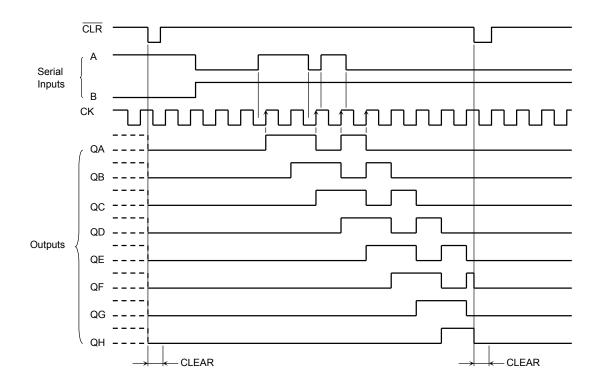
QAn to QGn: The level of QA to QG, respectively, before the most recent positive edge of the clock.

#### System Diagram



# <u>TOSHIBA</u>

# Timing Chart



### Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5 to 7.0	V
DC input voltage	VIN	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	lıк	±20	mA
Output diode current	IOK	±50	mA
DC output current	lout	±50	mA
DC V <sub>CC</sub> /ground current	ICC	±200	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP/TSSOP)	mW
Storage temperature	T <sub>stg</sub>	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = −40°C to 65°C. From Ta = 65°C to 85°C a derating factor of −10 mW/°C should be applied up to 300 mW.

### **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0 to 5.5	V	
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	V	
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V	
Operating temperature	T <sub>opr</sub>	-40 to 85	°C	
Input rise and fall time	dt/dV	0 to 100 (V <sub>CC</sub> = 3.3 ± 0.3 V)	ns/V	
	uvuv	0 to 20 (V <sub>CC</sub> = 5 $\pm$ 0.5 V)	ns/v	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	Symbol	Test Condition				Га = 25°С	)	Ta = −40 to 85°C		Unit		
Characteristics	Gymbol				V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max		
					2.0	1.50	_	_	1.50	_		
High-level input voltage	VIH		_		3.0	2.10	_	—	2.10	_	V	
				5.5	3.85	—	—	3.85	—			
					2.0	_	—	0.50	_	0.50		
Low-level input voltage	V <sub>IL</sub>		_		3.0	—	—	0.90	—	0.90	V	
ő					5.5	-	—	1.65	-	1.65		
	V <sub>OH</sub>				2.0	1.9	2.0	_	1.9	—		
		V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	3.0	2.9	3.0	—	2.9	—	v		
High-level output					4.5	4.4	4.5	_	4.4		-	
voltage			I <sub>OH</sub> = −4 mA		3.0	2.58	—	—	2.48	—	v	
			I <sub>OH</sub> = −24 mA		4.5	3.94	—	_	3.80	—		
			I <sub>OH</sub> = −75 mA	(Note)	5.5	-	—	—	3.85	-		
		V <sub>IN</sub> = V <sub>IH</sub> or			2.0	—	0.0	0.1	_	0.1		
	V <sub>OL</sub>		I <sub>OL</sub> = 50 μA		3.0	—	0.0	0.1	—	0.1		
Low-level output					4.5	_	0.0	0.1	_	0.1	V	
voltage		VIL	I <sub>OL</sub> = 12 mA		3.0	—	—	0.36	—	0.44	v	
			I <sub>OL</sub> = 24 mA		4.5	—	—	0.36	—	0.44		
			I <sub>OL</sub> = 75 mA	(Note)	5.5	_	_	—	_	1.65		
Input leakage current	lin	V <sub>IN</sub> = V <sub>C</sub>	<sub>C</sub> or GND		5.5	_	_	±0.1	_	±1.0	μA	
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>C</sub>	<sub>C</sub> or GND		5.5	_	—	8.0	_	80.0	μA	

Note: This spec indicates the capability of driving 50  $\Omega$  transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

#### Timing Requirements (input: t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C	Ta = −40 to 85°C	Unit	
	,		V <sub>CC</sub> (V)	Limit	Limit		
Minimum pulse width	t <sub>w (L)</sub>		3.3 ± 0.3	9.0	10.0		
(CK)	t <sub>w (H)</sub>	—	5.0 ± 0.5	5.0	6.0	ns	
Minimum pulse width			3.3 ± 0.3	9.0	10.0		
(CLR)	<sup>t</sup> w (L)	—	5.0 ± 0.5	5.0	6.0	ns	
	ts	_	3.3 ± 0.3	7.0	7.0	ns	
Minimum set-up time			5.0 ± 0.5	4.0	4.0		
			3.3 ± 0.3	1.0	1.0		
Minimum hold time	t <sub>h</sub>	—	5.0 ± 0.5	1.0	1.0	ns	
Minimum removal time	t <sub>rem</sub>	_	3.3 ± 0.3	8.5	8.5	ns	
( CLR )			5.0 ± 0.5	5.0	5.0		

#### AC Characteristics (C<sub>L</sub> = 50 pF, R<sub>L</sub> = 500 $\Omega$ , input: t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = −40 to 85°C		Unit
	- ,		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
Propagation delay time (CK-Q)	t <sub>pLH</sub> t <sub>pHL</sub>	_	3.3 ± 0.3 5.0 ± 0.5		9.6 6.6	16.3 9.8	1.0 1.0	18.6 11.2	ns
Propagation delay time ( CLR -Q)	tpHL	_	3.3 ± 0.3 5.0 ± 0.5	_	8.0 6.0	15.4 11.0	1.0 1.0	17.5 12.5	ns
Maximum clock frequency	f <sub>max</sub>	_	3.3 ± 0.3 5.0 ± 0.5	45 85	100 150	_	45 80	_	MHz
Input capacitance	C <sub>IN</sub>	_		_	5	10	_	10	pF
Power dissipation capacitance	C <sub>PD</sub>		(Note)	_	110	—	_	_	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

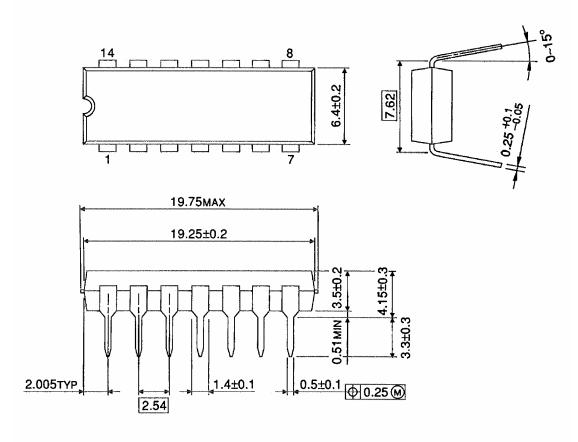
Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

### **Package Dimensions**

DIP14-P-300-2.54

Unit : mm



Weight: 0.96 g (typ.)

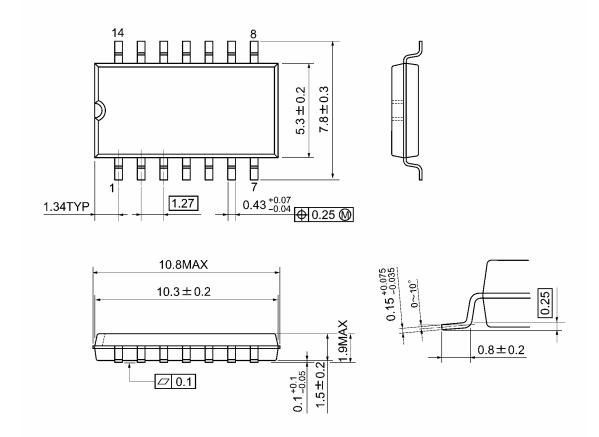
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### **Package Dimensions**

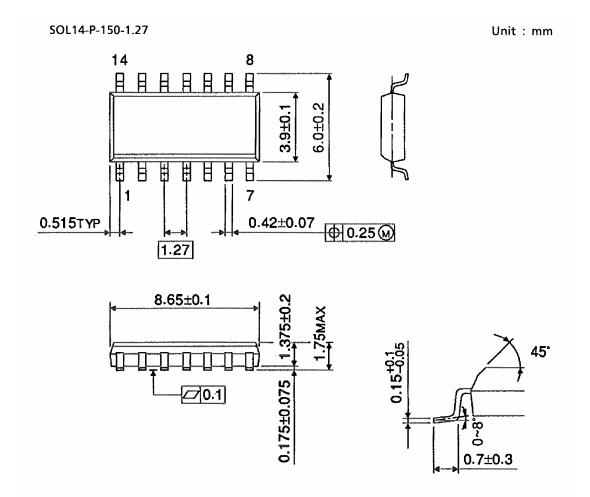
SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

#### Package Dimensions (Note)



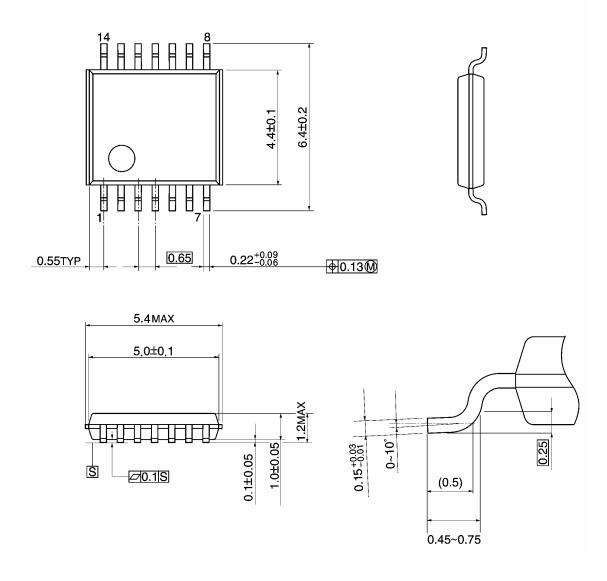
Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

# **Package Dimensions**

TSSOP14-P-0044-0.65A

Unit: mm



Weight: 0.06 g (typ.)

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20070701-EN GENERAL

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